

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

 Dependable Texas Instruments Quality and Reliability

description

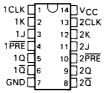
These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset input sets the outputs regardless of the levels of the other inputs. When preset (PRE) is inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The SN54LS113A and SN54S113 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LS113A and SN74S113A are characterized for operation from 0°C to 70°C.

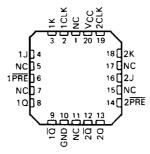
FUNCTION TABLE (each flip-flop)

	INPUT	OUTPUTS				
PRE	CLK	J	К	α	ā	
L	Х	×	х	Н	L	
н	1	L	L	a_0	$\overline{\alpha}_0$	
н	1	н	L	н	L	
н	1	L	н	L	Н	
н	ļ	Н	Н	TOGGLE		
н	Н	Х	х	۵n	۵n	

SN54LS113A, SN54S113 . . . J OR W PACKAGE SN74LS113A, SN74S113A . . . D OR N PACKAGE (TOP VIEW)

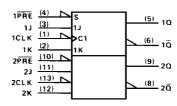


SN54LS113A, SN54S113 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic symbol[†]



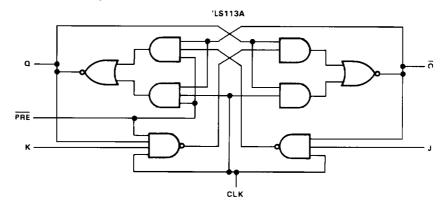
 † This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12

Pin numbers shown are for D, J, N, and W packages

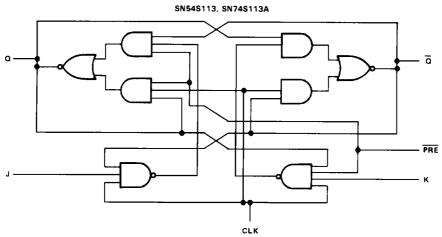
S

TTL Devices

logic diagrams (positive logic)

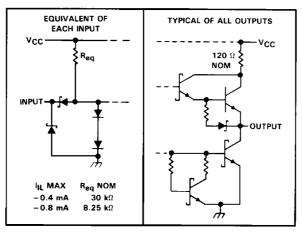


2 TTL Devices

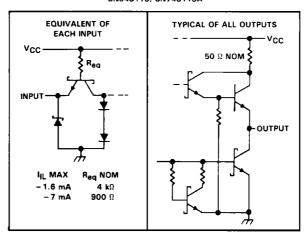


schematics of inputs and outputs

'LS113A



SN54S113, SN74S113A



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)
Input voltage: 'LS113A
SN54S113, SN74S113A5.5 N
Operating free-air temperature range: SN54'55°C to 125°C
SN74′
Storage temperature range

NOTE 1: Voltage values are with respect to network ground terminals.



SN54LS113A, SN74LS113A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET

recommended operating conditions

			SN	154LS11	ЗА	SN74LS113A			
			MiN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4 5	5	5 5	4.75	5	5.25	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
ЮН	High-level output current				-0.4			-0.4	mA
lol	Low-level output current				4			8	mA
f _{clock}	Clack frequency		0		30	0		30	MHz
	Pulse duration	CLK high	20			20			
tw	ruise duration	PRE or CLR low	25		-	25			ns
	Set up time-before CLK↓	Data high or low 20			_	20			
t _{su}	Set up time-before CEK¢	PRE inactive	20			20			ns
th	Hold time-data after CLK↓		0		-	0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

					SN54LS113A			SN	3A	Ī		
PARAMETER		TEST	CONDITIONS		MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT	
Vik		V _{CC} = MIN,	I _I = -18 mA				-15			-15	٧	
Voн		$V_{CC} = MIN,$ $I_{OH} = -0.4 \text{ mA}$	V _{IH} = 2 V,	VIL = MAX,	2 5	3 4		2 7	3 4		V	
		V _{CC} = MIN, I _{OL} = 4 mA	V _{IL} = MAX,	V _{IH} = 2 V,		0 25	0 4		0 25	0.4	T	
VOL		V _{CC} = MIN, I _{OL} = 8 mA	VIL = MAX,	V _{IH} = 2 V.					0 35	0.5	- v	
	J or K						0.1			0.1		
l _l	PRE	VCC = MAX.	$V_1 = 7 V$				0.3			0.3	mA	
	ČLK					0.4			0 4			
	J or K			-			20			20	-	
Ιн	PRE	V _{CC} = MAX,	$V_1 = 27 V$				60			60	μА	
	CLK						80			80	7	
le.	J or K	V _{CC} = MAX,	V: = 0.4.V				-04			-04	mA	
IL	PRE or CLK	T ACC = MINY	V = U 4 V				-08			- 0 8	IIIA	
los §		V _{CC} = MAX.	see Note 2		- 20		- 100	- 20		- 100	mA	
ICC IT	otal)	V _{CC} = MAX,	see Note 3			4	6		4	6	mA	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions



 $^{^{\}ddagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 \, ^{\circ}\text{C}$

Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second

NOTES 2 For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with $V_Q = 2.25 \text{ V}$ and 2.125 V for the '54 family and the '74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values

³ With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

SN54LS113A, SN74LS113A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET

switching characteristics, VCC = 5 V, TA = 25 °C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	TYP	MAX	UNIT	
fmax					30	45		MHz
^t PLH	PRE or CLK	Q or ₫	$R_L = 2 k\Omega$, C_L	= 15 pF		15	20	ns
tPHL_	THE OF CER	4014				15	20	ns

NOTE 4: Load circuits and voltage waveforms are shown in Section 1.

			MIN	NOM	MAX	MIN	NOM	MAX	ı
vcc .	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	V
юн	High-level output current	_			- 1			- 1	mA
lOL	Low-level output current				20			20	mA
tw		CLK high	6			6			
	Pulse duration	CLK low	6.5			6.5			ns
		PRE low	8			8			l
t _{su}	Set up time-before CLK↓	Data high or low	7	_		7			ns
th	Hold time-data after CLK↓		0			0			пѕ
TA	Operating free-air temperature		- 55		125	0		70	°C

SN54S113

SN74S113A

noted)

					SN54S113			SN74S113A			
PA	RAMETER	TEST	CONDITIONS		MIN	TYP [‡]	MAX	MIN	TYP‡	MAX	UNIT
VIK		V _{CC} = MIN,	I _I = -18 mA				-1.2			-1.2	٧
VOH		V _{CC} = MIN, I _{OH} = -1 mA	V _{IH} ≈ 2 V,	V _{IL} = 0.8 V,	2.5	3.4	-	2.7	3.4		٧
VOL		V _{CC} = MIN, I _{OL} = 20 mA	V _{IH} = 2 V.	V _{IL} ≃ 0.8 V,			0.5			0.5	V
կ		V _{CC} = MAX.	V _I = 55 V				1			1	mA
	J or K	VCC = MAX,	V: - 2.7.V				50			50	μA
ŀН	PRE or CLK	VCC = WAX,	VI = 2.7 V				100			100	μπ
	J or K		_				-1.6			- 1.6	
ηL	PRE 5	VCC = MAX.	$V_{I} = 0.5 V$				- 7			- 7	mA
	CLK §	1					-4			-4	
los¶	····	V _{CC} = MAX			-40		- 100	-40		- 100	mA
ICC#		V _{CC} = MAX,	see Note 3			15	25		15	25	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25 °C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax				80	125		MHz
tPLH	PRE	Q or Q			4	7	ns
	PRE (CLK high)	ā or ā	7 3000 0 15-5		5	7	
^t PHL	PRE (CLK low)		$R_L = 280 \Omega$, $C_L = 15 pF$		5	7	ns
tPLH	CLK		1		4	7	ns
tpHL	CLK				5	7	ns

NOTE 4 Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at V_{CC} = 5 V, T_A = 25 °C

[§] Clear is tested with preset high and preset is tested with clear high.

Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

[#]Values are average per flip-flop

NOTE 3. With all outputs open. ICC is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is